

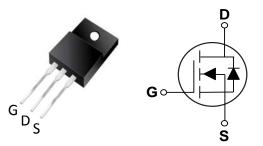
Pb RoHS

General Description

The I2MNAB900 is a high voltage power MOSFET designed to have better characteristics, such as fast switching time, low gate charge, low on-state resistance and have a high rugged avalanche characteristic.

This power MOSFET is usually used in high speed switching applications including power supplies, PWM motor controls, high efficient AC to DC converters and bridge circuits.

TO-220F Pin Configuration



BV _{DSS}	R _{DS(ON)}	I _D
650 V	0.9 Ω	10 A

Features

- $R_{DS(ON)} \le 0.9 \Omega @V_{GS}$ =10V
- Fast Switching Capability
- Improved dv/dt Capability

Absolute Maximum Ratings T _c =25°C unless otherwise noted						
Symbol	Symbol Parameter		Units			
V _{DS}	Drain-Source Voltage	650	V			
V _{GS}	Gate-Source Voltage	±30	V			
I _D	Drain Current - Continuous	10	Α			
I _{DM}	Drain Current - Pulsed (NOTE 2)	20	Α			
EAS	Single Pulse Avalanche Energy (NOTE 3)	840	mJ			
P _D	Power Dissipation	38	W			
TJ	Operating Junction Temperature Range	-50 to 150	°C			
T _{STG}	Storage Temperature Range	-50 to 150	°C			
Marking Code		NAB900				

NOTES :

1. Absolute maximum ratings are those values beyond which the device could be permanently damaged.

Absolute maximum ratings are stress ratings only and functional device operation is not implied.

- 2. Repetitive Rating: Pulse width limited by maximum junction temperature.
- 3. L=100mH, V_{DD} =50V, R_G =25 Ω , Starting T_J = 25°C

Thermal Characteristics

Symbol	Parameter		Max.	Unit
R _{θJA}	Thermal Resistance Junction to Ambient		62.5	°C/W
R _{θJC}	Thermal Resistance Junction to Case		3.28	°C/W





Electrical Characteristics (T_J=25°C, unless otherwise noted)

Off Characteristics						
Symbol	Parameter	Conditions	Min.	Тур.	Max.	Unit
BV_{DSS}	Drain-Source Breakdown Voltage	V _{GS} =0V , I _D =250uA	650			V
I _{DSS}	Drain-Source Leakage Current	V _{DS} =650V , V _{GS} =0V			10	uA
I _{GSS}	Gate-Source Leakage Current	V_{GS} =±30V , V_{DS} =0V			±100	nA

On Characteristics

Symbol	Parameter	Conditions	Min.	Тур.	Max.	Unit
R _{DS(ON)}	Static Drain-Source On-Resistance	V _{GS} =10V , I _D =5A		0.75	0.9	Ω
V _{GS(th)}	Gate Threshold Voltage	$V_{GS}=V_{DS}$, $I_{D}=250$ uA	2.0		4.0	V

Dynamic and switching Characteristics

Symbol	Parameter	Conditions	Min.	Тур.	Max.	Unit
Qg	Total Gate Charge	V_{DS} =520V , V_{GS} =10V , I_{D} =10A ,		34		
Q _{gs}	Gate-Source Charge	I _G =1mA		12		nC
Q _{gd}	Gate-Drain Charge	(NOTE 4 \ 5)		7.4		
T _{d(on)}	Turn-On Delay Time			26		
Tr	Rise Time	V _{DS} =325V , V _{GS} =10V , R _G =25Ω , I _D =10A		21		ns
T _{d(off)}	Turn-Off Delay Time	(NOTE 4 \ 5)		80		115
T _f	Fall Time			23		
C _{iss}	Input Capacitance			1554		
C _{oss}	Output Capacitance	V _{DS} =25V , V _{GS} =0V , F=1MHz		158		pF
C _{rss}	Reverse Transfer Capacitance	7		4.4		

Drain-Source Diode Characteristics and Ratings

Symbol	Parameter	Conditions	Min.	Тур.	Max.	Unit
۱ _s	Continuous Source Current				10	А
I _{SM}	Pulsed Source Current				40	Α
V_{SD}	Diode Forward Voltage	V _{GS} =0V , I _S =10A			1.4	V
trr		I _S =10A , V _{GS} =0V ,		375		nS
Qrr	Reverse Recovery Charge	dl _F /dt=100A/µs (NOTE 4)		5.2		uC

NOTES :

4. Pulse test : pulse width \leq 300us , duty cycle \leq 2%.

5. Essentially independent of operating temperature.





Test Circuits And Waveforms

FIG. 1-Peak Diode Recovery dv/dt Test Circuit

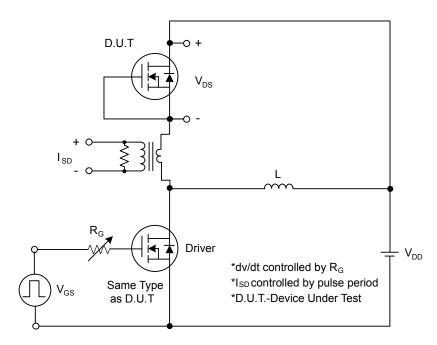
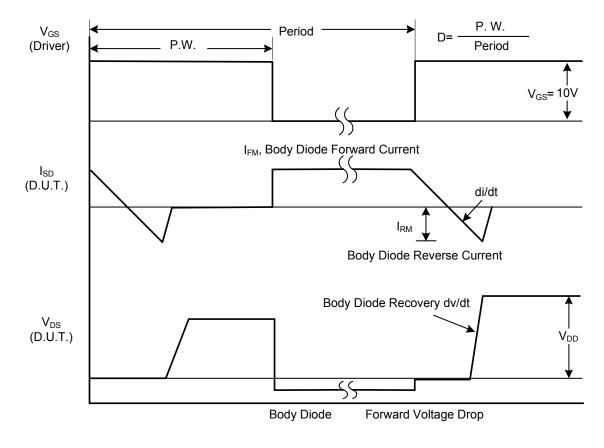


FIG. 2-Peak Diode Recovery dv/dt Waveforms





Pb RoHS

Test Circuits And Waveforms

FIG. 3-Switching Test Circuit

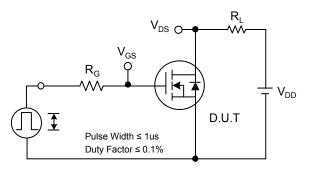


FIG. 4-Switching Waveforms

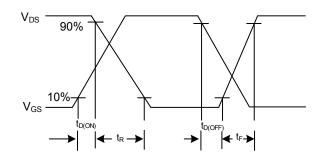


FIG. 5-Gate Charge Test Circuit

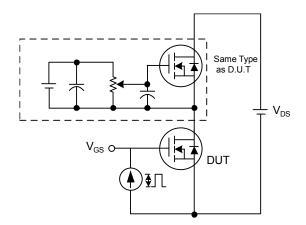


FIG. 7-Unclamped Inductive Switching Test Circuit

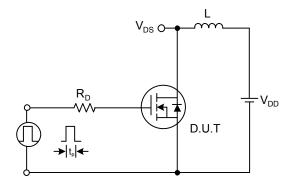


FIG. 6-Gate Charge Waveform

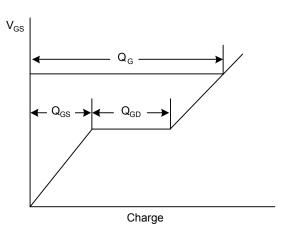
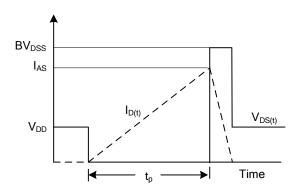


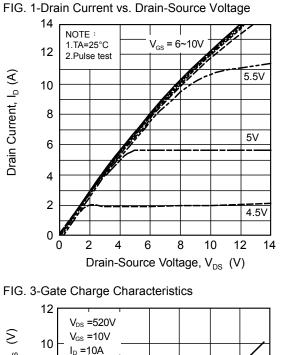
FIG. 8-Unclamped Inductive Switching Waveforms

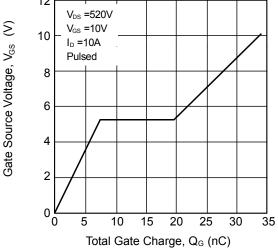


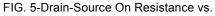


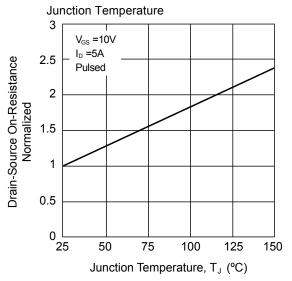
P-b RoHS

Characteristics Curves









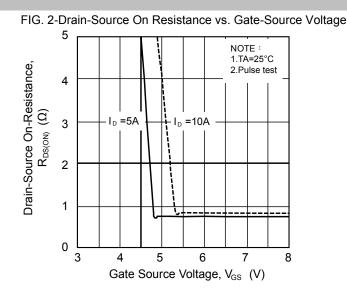


FIG. 4-Capacitance Characteristics

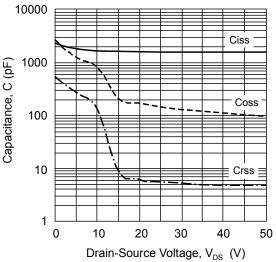
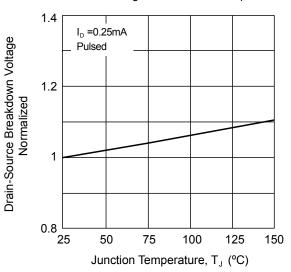


FIG. 6-Breakdown Voltage vs. Junction Temperature





Pb RoHS

Characteristics Curves

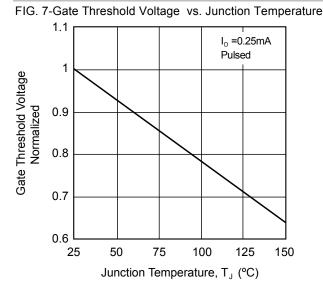


FIG. 9-Drain Current vs. Gate-Source Voltage

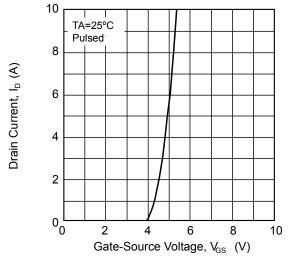
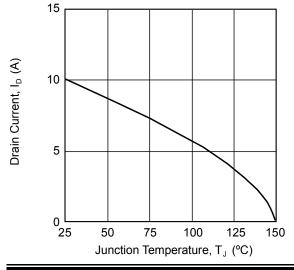


FIG. 11-Drain Current vs. Junction Temperature



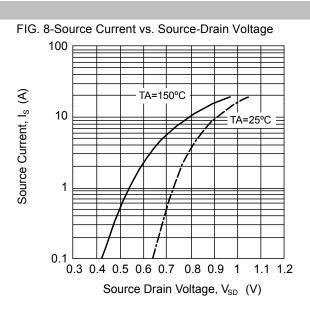
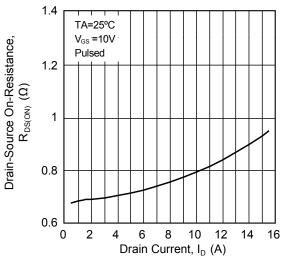


FIG. 10-Drain-Source On Resistance vs. Drain Current

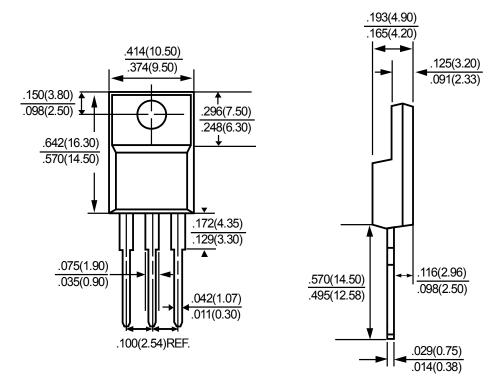




Pb RoHS

650V N-Channel MOSFETs

Package Outline Dimensions



TO-220F Dimensions in inches and (millimeters)



LEGAL DISCLAIMER

- The product is provided "AS IS" without any guarantees or warranty. In association with the product, Eris Technology Corporation, its affiliates, and their directors, officers, employees, agents, successors and assigns (collectively, the "Eris") makes no warranties of any kind, either express or implied, including but not limited to warranties of merchantability, fitness for a particular purpose, of title, or of non-infringement of third party rights.
- The information in this document and any product described herein are subject to change without notice and should not be construed as a commitment by Eris. Eris assumes no responsibility for any errors that may appear in this document.
- Eris does not assume any liability arising out of the application or use of this document or any product described herein, any Customer or user of this document or products described herein in such applications shall assume all risks of such use and will agree to hold Eris and all the companies whose products are represented on Eris website, harmless against all damages.
- No license, express or implied, by estoppels or otherwise, to any intellectual property is granted by this document or by any conduct of Eris. Product name and markings notes herein may be trademarks of their respective owners.
- Eris does not warrant or accept any liability whatsoever in respect of any products purchased through unauthorized sales channel.
- Should Customers purchase or use Eris products for any unintended or unauthorized application, Customers shall indemnify and hold Eris and its representatives harmless against all claims, damages, expenses, and attorney fees arising out of, directly or indirectly, any claim of personal injury or death associated with such unintended or unauthorized application.
- The official text is written in English and the English version of this document is the only version endorsed by Eris. Any discrepancies or differences created in the translations are not binding and have no legal effect on Eris for compliance or enforcement purposes.